

INTERNATIONAL STANDARD

AMENDMENT 20

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**Mechanical standardization of semiconductor devices –
Part 2: Dimensions**

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INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

ICS 31.080.01

ISBN 978-2-8322-5566-7

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INSTRUCTIONS FOR THE INSERTION
OF NEW PAGES IN IEC 60191-2

Replace the existing title page with the new title page.

Remove the existing page 60191 IEC I containing the preface and insert in its place the new page 60191 IEC I containing the preface to Amendment 20 (2018).

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Add the following new sheets:

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60191 IEC I-189F-a/b

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J (1980), K (1981), L (1982), M (1983), N (1987), P (1988), Q (1990), R (1995),
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INTERNATIONAL ELECTROTECHNICAL COMMISSION

PUBLICATION 191-2

MECHANICAL STANDARDIZATION OF SEMICONDUCTOR DEVICES –

Part 2: Dimensions

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IEC 60191-2:1966/AMD20:2018

IEC Publication 191-2
Date: 1987

INTERNATIONAL ELECTROTECHNICAL COMMISSION

Amendment 20 (2018) to IEC 60191-2 (1966)

MECHANICAL STANDARDIZATION OF SEMICONDUCTOR DEVICES –

Part 2: Dimensions

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PREFACE TO AMENDMENT 20 (2018)

This amendment has been prepared by subcommittee 47D: Semiconductor Packaging, of IEC technical committee 47: Semiconductor devices.

The text of this standard is based on the following documents:

FDIS	Report on voting
47D/900/FDIS	47D/906/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

CHAPTER I – DEVICE OUTLINE DRAWINGS

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